CRYSTAL SPECIFICATION

Product Code : C7M1356020AFSAF0-QE04

Description : Quartz Crystal

Revision History

Rev.	Date	Reason	Issued By
0	29/12/2014		szom_xiaopei

CRYSTAL SPECIFICATION

Customer	:
End User	: 上海旭谷國際貿易有限司
Customer Part No.	: C7M1356020AFSAF0-QE04
Product Code	: C7M1356020AFSAF0-QE04
Description	: Quartz Crystal
Nominal Frequency	: 13.560 MHz
Oscillation Mode	: Fundamental
Holder Type	: C7

Measure equipment

Electrical characteristics measured by Kolinker KH1240 or HP5100 equivalent.

Electrical Characteristics :

Load Capacitance	20 pF
Frequency Tolerance At 25 °C	± 10 ppm
Frequency Stability	± 50 ppm
Operating Temperature Range	-40 ~ 85 °C
Storage Temperature Range	-45 ~ 90 °C
Aging	<± 5 ppm first year
Drive Level	50 μW
Equivalent Series Resistance	150 ohms Max.
Shunt Capacitance	7 pF Max.
Insulation Resistance	500M ohm Min at 100 VDC
Marking	13.560+LOT NO.

Remarks for Customer Specifications :

Application	BCM
Remark	SPQ 3K/R



ALL DIMENSIONS IN mm UNLESS OTHERWISE STATED

SCALE: NA

SHT. 1 OF 1

REV. 01

PROPERTY OF HKC.



<u>SIDE VIEW</u>

ITEM	DESCRIPTION	MATERIAL		
1	C⊡NDUCTI∨E B⊡NDING	EPOXY		
2	ELECTRODE	Ag		
3	EDGE	Ag-Cu Alloy		
4	SUBSTRATE	CERAMIC		
5	COVER (LID)	Fe-Ni-Co Alloy		
6	BLANK	SYNTHETIC QUARTZ		

		INTERNAL STRUCTURE								
ITEM	ITEM QTY. DESCRIPTION		MAT'L	HDN.	SURFACE	MAT'L	SIZE	F	REMARK	
GENERAL TOLERANCE: X=±0.5 X°=±0.5° .X=±0.1 .X°=±0.1° .XX=±0.05 .XX°=±0.05°			DATE	NAME						
		DRAWN	16-03-10	Deng			CERAMIC SMD TYPE CRYSTAL(4PADS		AL(4PADS)	
		CHECK	16-03-10	Hong			CROSS SECTION			
PROPRIETARY NOTICE : THIS DRAWINGS AND SPECIFICATIONS ARE THE PROPERTY OF KOLINKER		APROV.	16-03-10				PART No.: (C1 C3 C5	C7 C4	4
			HONG KONG X'TALS LTD.			DRAWING No.:	1203795	6		
DO NOT SCALE DRAWING A		ALL D	ALL DIMENSIONS IN mm UNLESS OTHERWISE STATED			SCALE:NA	SHT. 1 OF	1	rev. 01	





Hong Kong X'tals Limited Hong Kong Automotive X'tals Limited Unit L-M, 24/F, Shield Industrial Center, 84 - 92 Chai Wan Kok Street, Tsuen Wan, New Territories, Hong Kong. Tel: (852) 35112388 Fax: (852) 35112420 Email : hkxtals@hongkongcrystal.com

AEC-Q200-Rev D Reliability Test for Quartz Crystal

Drawing No. : 12080065 rev. 00

Reliability Test	Condition of Test	Requirements
1. Pre-and Post-Stress Electrical Test	Test is performed except as specified in the applicable stress reference and the additional requirements in this table.	All Electrical Functions must meet with the specifications. Note: *Generic data allowed.
2. TEST NOT USED	-	-
3. High Temperature Exposure (Storage)	MIL-STD-202 Method 108 1000 hrs. at rated operating temperature (e.g. 85° C part can be stored for 1000 hrs at 85° C. The same applies for 125° C). Unpowered. Measurement at 24 ± 2 hours after test conclusion.	All Electrical Functions must meet with the specifications. Note: *Generic data allowed. **Devices are not to be reused for qualification or production.
4. Temperature Cycling	JESD22 Method JA-104 1000 cycles (-40°C to 125°C) Note: If 85°C part the 1000 cycles will be at that temperature rating. Measurement at 24±2 hours after test conclusion.	Ditto Note: *Generic data allowed. **Devices are not to be reused for qualification or production.
5. TEST NOT USED	-	-
6. TEST NOT USED	-	-
7. Biased Humidity	MIL-STD-202 Method 103 1000 hours 85 °C/85% RH. Rated VDD applied with 1 M Ω and inverter in parallel, 2X crystal CL capacitors between each crystal leg and GND. Measurement at 24±2 hours after test conclusion.	Ditto Note: *Generic data allowed. **Devices are not to be reused for qualification or production.
8. Operational Life	MIL-STD-202 Method 108 Note: 1000 hrs @ 125°C. If 85°C part will be tested at that temperature. Rated VDD applied with 1M Ω and inverter in parallel, 2X crystal CL capacitors between each crystal leg and GND. Measurement at 24±2 hours after test conclusion.	Ditto Note: *Generic data allowed. **Devices are not to be reused for qualification or production.
9. External Visual	MIL-STD-883 Method 2009 Inspect device construction, marking and workmanship. Electrical Test not required.	Parts should meet with the criteria presents by MIL- STD-883 Method 2009 Note: *Generic data allowed. **Devices can be used to populate other tests or they can be used for production.
10. Physical Dimension	JESD22 Method JB-100 Verify physical dimensions to the applicable device detail specification. Note: User(s) and Suppliers spec. Electrical Test not required.	Dimensions should meet with the specification. Note: *Generic data allowed. **Devices can be used to populate other tests or they can be used for production.



Hong Kong X'tals Limited Hong Kong Automotive X'tals Limited Unit L-M, 24/F, Shield Industrial Center, 84 - 92 Chai Wan Kok Street, Tsuen Wan, New Territories, Hong Kong. Tel: (852) 35112388 Fax: (852) 35112420 Email : hkxtals@hongkongcrystal.com

11. Terminal Strength (Leaded)	MIL-STD-202 Method 211 Test leaded device lead integrity only.	All Electrical Functions must meet with the specifications.
	 A (227 g) - Pull test - also known as a tension or tensile test for terminals. It is usually applicable to most types of terminals. C (227 g): Wire-lead bend test - also known as a lead-fatigue, bend, or flexibility test. It is applicable to solid-wire-lead terminals of limited ductility, such as nickel-alloy-type leads and those used in hermetically-sealed component parts. 	*Generic data allowed. **Devices are not to be reused for qualification or production. ***Required for leaded devices only.
12. Resistance to Solvents	MIL-STD-202 Method 215 Note: Also aqueous wash chemical - OKEM clean or equivalent. Do not use banned solvents.	No deterioration in marking Note: *Generic data allowed. **Devices are not to be reused for qualification or production.
13. Mechanical Shock	MIL-STD-202 Method 213 Figure 1 of Method 213. Condition C	All Electrical Functions must meet with the specifications. Note: *Generic data allowed. *Devices are not to be reused for qualification or production.
14. Vibration	MIL-STD-202 Method 204 5g's for 20 minutes 12 cycles each of 3 orientations. Note: Use 8"X5" PCB .031" thick with 7 secure points on one 8" side and 2 secure points on corners of opposite sides. Parts mounted within 2" from any secure point. Test from 10-2000 Hz.	Ditto Note: *Generic data allowed. **Devices are not to be reused for qualification or production.
15. Resistance to Soldering Heat	MIL-STD-202 Method 210 Condition B No pre-heat of samples. Note: Single Wave solder - Procedure 1 with solder within 1.5mm of device body for Leaded. Procedure 1 except 230°C and immerse only to level to cover terminals for SMD.	Ditto Note: *Generic data allowed. **Devices are not to be reused for qualification or production. **The solderability (test #18) and resistance to solder heat (test #15) tests are still required to be performed on Pb-free product for backward compatibility with Pb processes.
16. TEST NOT USED	-	-
17. TEST NOT USED	-	-
18. Solderability	J-STD-002 For both Leaded & SMD. Electrical Test not required. Magnification 50 X. Conditions: Leaded: Method A @235°C, category 3. SMD: a) Method B, 4 hrs @155°C dry heat @235°C b) Method B @215°C category 3. c) Method D category 3 @ 260°C.	Solder should cover at least 95% of the surface being tested. Note: *Devices are not to be reused for qualification or production. **The solderability (test #18) and resistance to solder heat (test #15) tests are still required to be performed on Pb-free product for backward compatibility with Pb processes.



Hong Kong X'tals Limited Hong Kong Automotive X'tals Limited Unit L-M, 24/F, Shield Industrial Center, 84 - 92 Chai Wan Kok Street, Tsuen Wan, New Territories, Hong Kong. Tel: (852) 35112388 Fax: (852) 35112420 Email : hkxtals@hongkongcrystal.com

19. Electrical Characterization	User Spec.	All Electrical Functions must
	Parametrically test per lot and sample size	meet with the specifications.
	requirements, summary to show Min, Max, Mean	Note:
	and Standard deviation at room as well as Min and	*Generic data allowed.
	Max operating temperatures	**Devices can be used to populate
	than operating temperatures.	other tests or they can be used for
2 0 E		production.
20. Flammability	UL-94	V-0 or V-1 Acceptable.
		Note:
		*Devices are not to be reused for
01 D 1 E		qualification or production.
21. Board Flex	AEC-Q200-005	A failure is when a part
	Note: 2mm (Min)	cracks or causes a change in
	60 sec minimum holding time	the parametric being
		monitored.
		Note:
		*Devices are not to be reused for
		qualification or production.
		**Required for surface mount
22 Terminal Strongth (SMD)	AEC 0200 006	The failure criteria are
22. Terminal Strength (SMD)	ALC-Q200-000 Note: A former of 1 Plus for 60 seconds	accordent to the section of the
	Note: A force of 1.8kg for 60 seconds.	governed by not meeting the
		device specification, along
		with evidence of cracking or
		part being sheared off from
		its pad.
		Note:
		*Devices are not to be reused for
		qualification or production.
		**Required for surface mount
		devices only.

12080065 rev. 00

